



SiPM characteristics after very high Radiation at low Temperature for the SLHC CMS PHASE II upgrade

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Outline



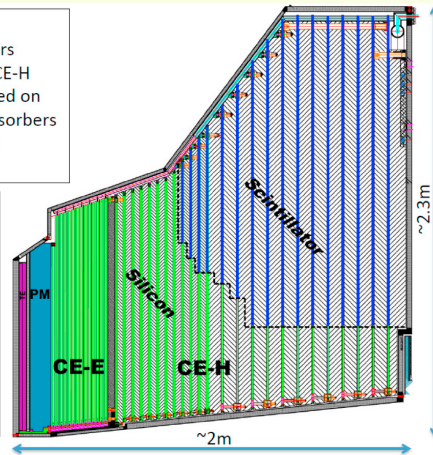
- 2 future CMS sub detectors which are planning on using SiPMs
- General experience from last > 10 years of R&D on radiation on SiPMs
- Results of latest Wafer run with FBK on thin epitaxial layer substrate
- Main effects of radiation at very high doses > $5E13$ n/cm² 1 Mev eq

Active Elements:

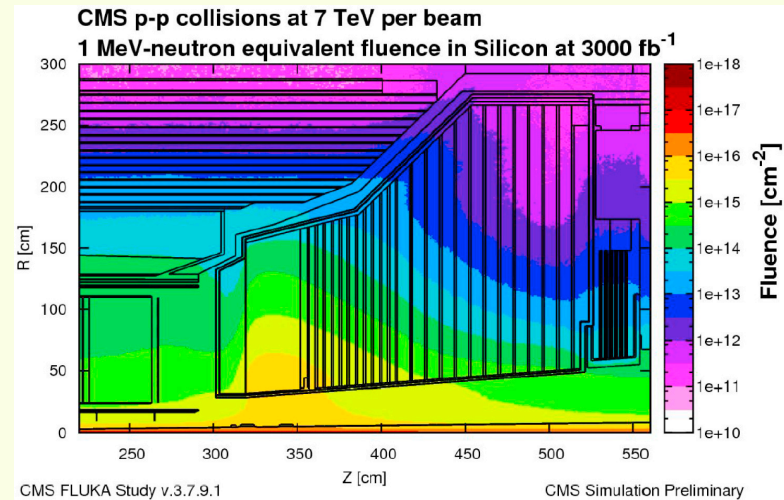
- Hexagonal modules based on Si sensors in CE-E and high-radiation regions of CE-H
- "Cassettes": multiple modules mounted on cooling plates with electronics and absorbers
- Scintillating tiles with SiPM readout in low-radiation regions of CE-H

Key Parameters:

- CE covers $1.5 < \eta < 3.0$
- ~ 215 tonnes per endcap
- Full system maintained at -30°C
- $\sim 600\text{m}^2$ of silicon sensors
- $\sim 500\text{m}^2$ of scintillators
- 6M si channels, 0.5 or 1 cm^2 cell size
- ~ 27000 si modules
- Power at end of HL-LHC: ~ 110 kW per endcap



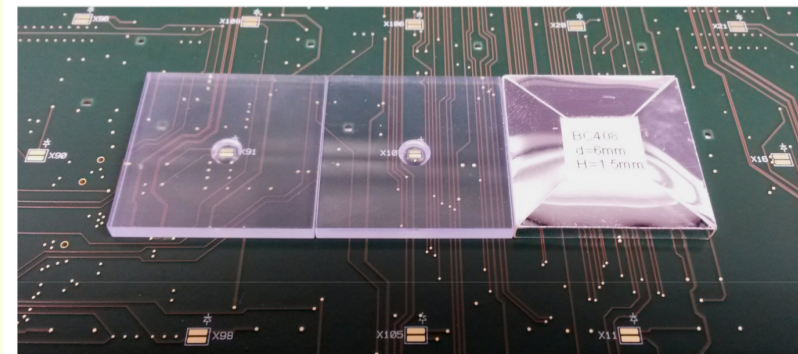
Electromagnetic calorimeter (CE-E): Si, Cu & CuW & Pb absorbers, 28 layers, $25 X_0$ & $\sim 1.3\lambda$.
 Hadronic calorimeter (CE-H): Si & scintillator, steel absorbers, 24 layers, $\sim 8.5\lambda$.



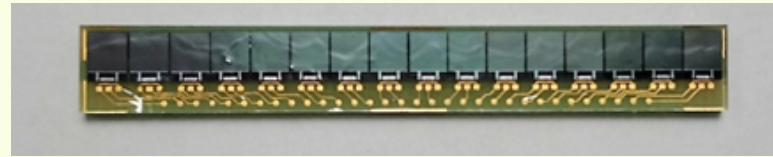
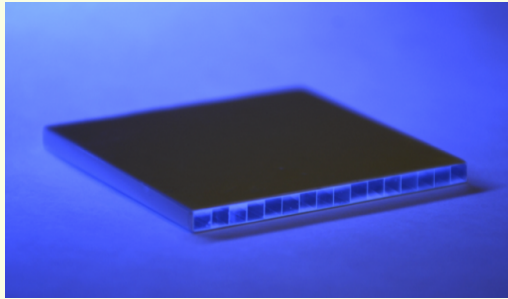
1 Mev eq Neutron fluence up to $8E13 \text{ n/cm}^2$

We expect a signal of $\sim 40 \text{ p.e./MIP}$

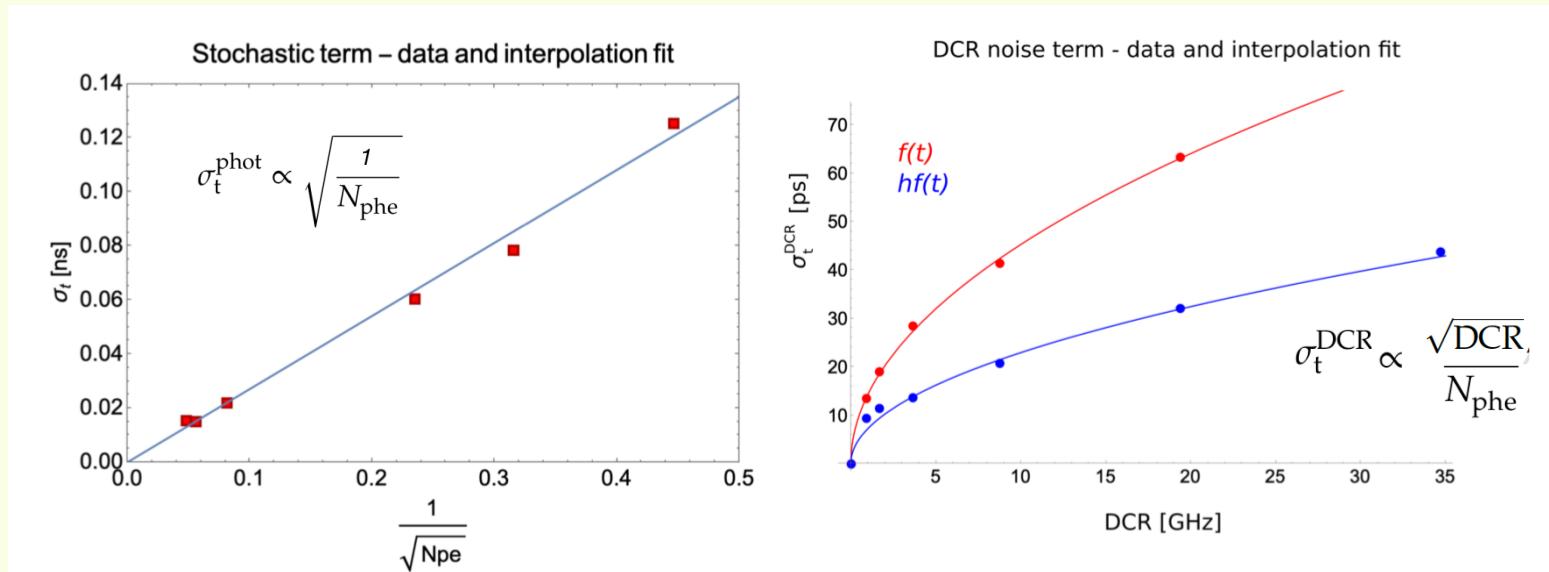
Signal to Noise is very important for calibration



SiPM-on-Tile in the biggest part of CE for high granularity to compliment CE-E

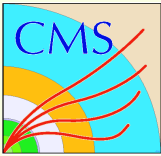


SiPM array to readout LYSO array (2 sides)



Bench measurement of the timing dependence of the N_{phe} and DCR using an LED with a pulse of 390 p.e. and time spread of 350 ps rms.

At $2E14$ n/cm² eq. the DCR is expected to rise to 40-60 GHz even at an operating temperature inside the tracker tube of -30C . The DCR noise term will quickly be the dominating factor in the timing resolution.

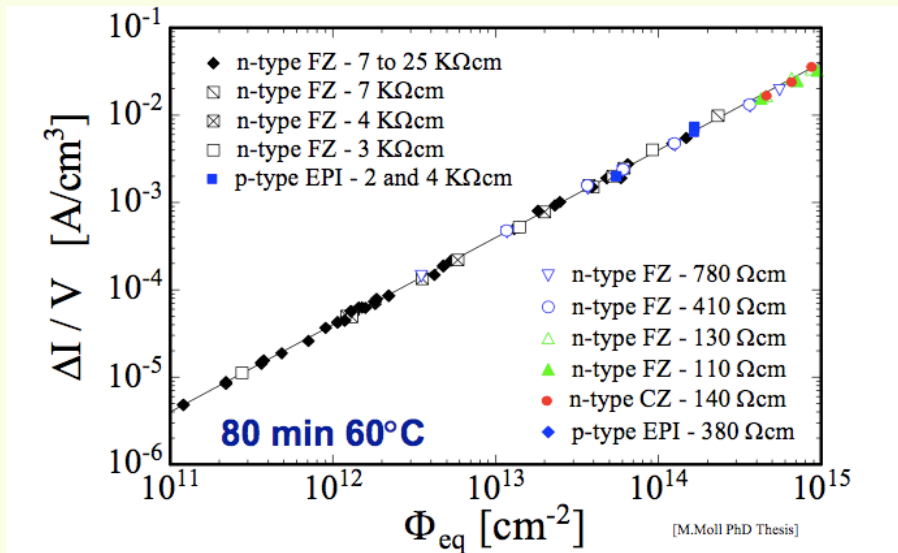


DCR or Noise increase in SiPMs due to rad

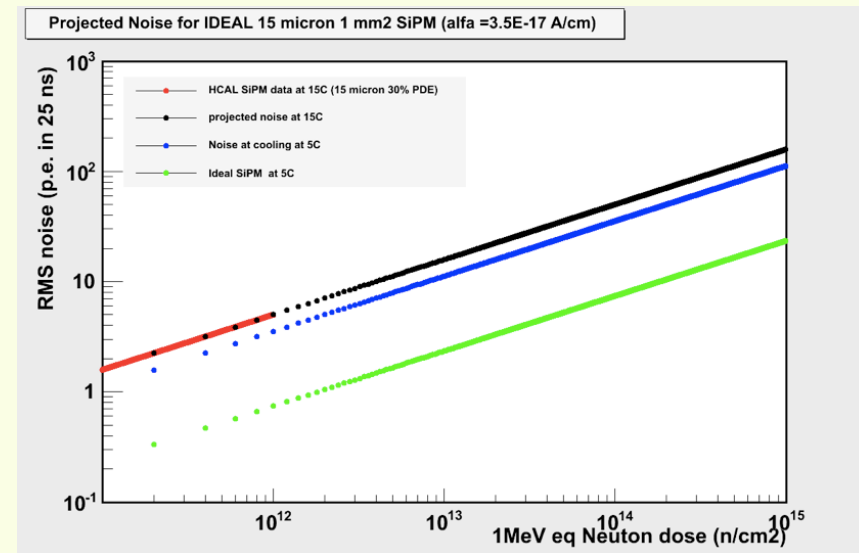


Leakage current increase in Si-PIN diodes for 1 MeV equivalent dose

slope= $3.5E-17$ A/cm



Measurements show ~4X more noise

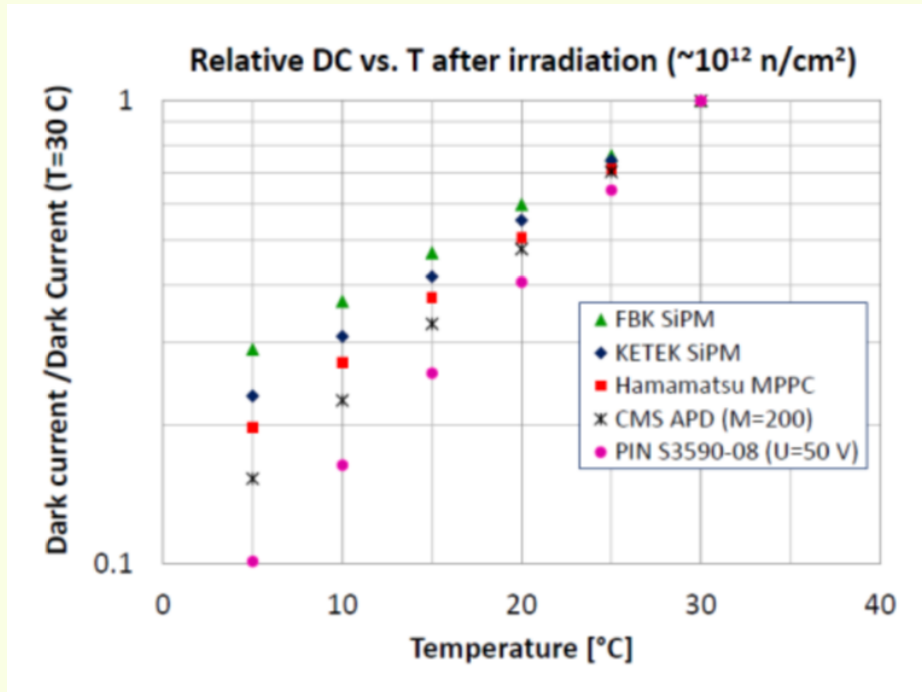


We expect the dark count rate:

$$\text{Dark Count} = 1/q * V * \Phi * \text{slope} * G.F. * P_{(V)}$$

$$V = \text{cell size} * d_{epi} \text{ (few microns in case of SiPM)}$$

The dark noise generation rate in APDs/SiPMs is dominated by high electric field effects mainly by tunneling via radiation-induced defects or traps in Si

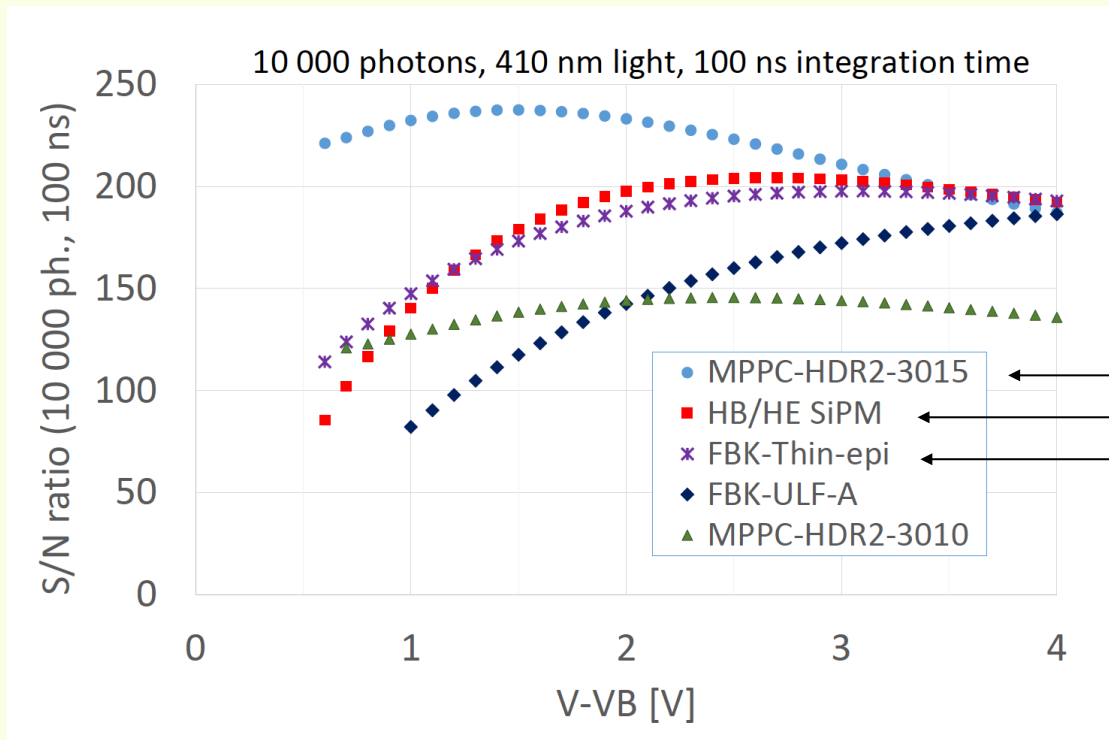


Before Irradiation:

Primary dark count rate is due to the thermal generation of carriers; $1/T$ (reduction of 2.4 x every 10C)

After irradiation we find that

temperature reduction coefficient drops to as low as 1.6 / 10C depending on the internal electric field structure of the SiPM
 General trend is that SiPMs with higher V_{br} have larger reduction with T



TDR baseline
SiPMs for BTL

In 2018 we chose the best 3 SiPMs with the best performance vs irradiation for the BTL as a TDR baseline. All cell sizes are 15x15 micron to avoid saturation due to high DCR. This also reduces the recovery time



FBK wafer split for optimization



Wafer n.	Substrate	Technology	DI dose	Meas Vbr (RT)
1	Thin Epi	Low Field	1	
2	Thin Epi	Low Field	1	38.0
3	Thin Epi	Low Field	2	
4	Thin Epi	Low Field	2	35.2
5	Thin Epi	Low Field	2	
6	Thin Epi	Low Field	3	
7	Thin Epi	Low Field	3	33.0
8	Thin Epi	Low Field	4	
9	Thin Epi	Low Field	4	32.0
10	Thin Epi	Low Field	4	

DI dose

} smaller

} TDR Thin epi

} larger

} largest

In addition each wafer has 2 different micro cell versions
one aggressive for better FF

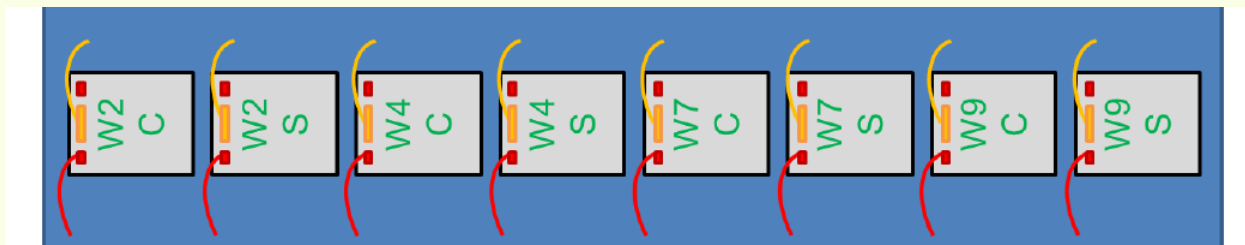
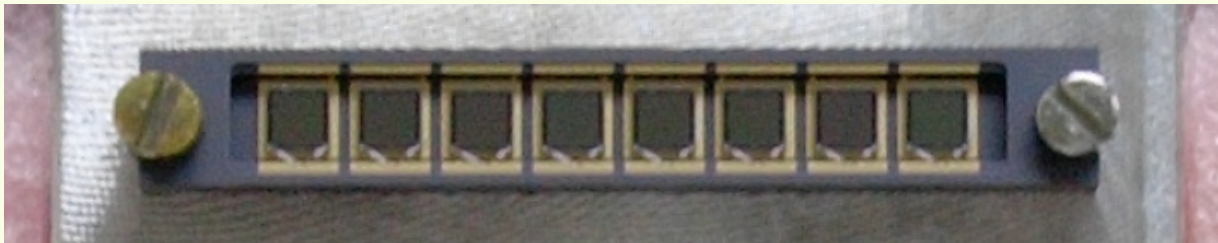
15 micron STD : 51.2 %

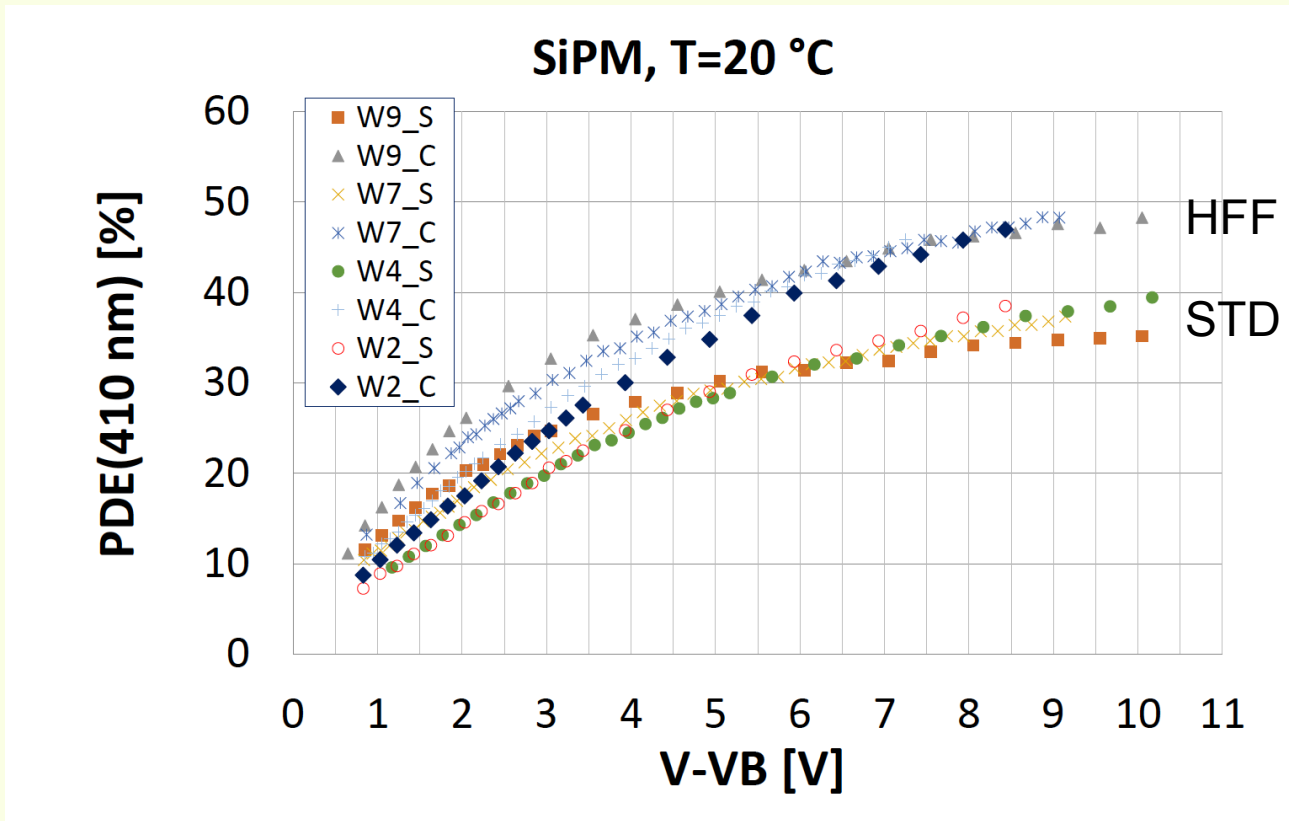
15 micron HFF : 60.1 %

We packaged the 8 different Types in a 8ch ceramic package

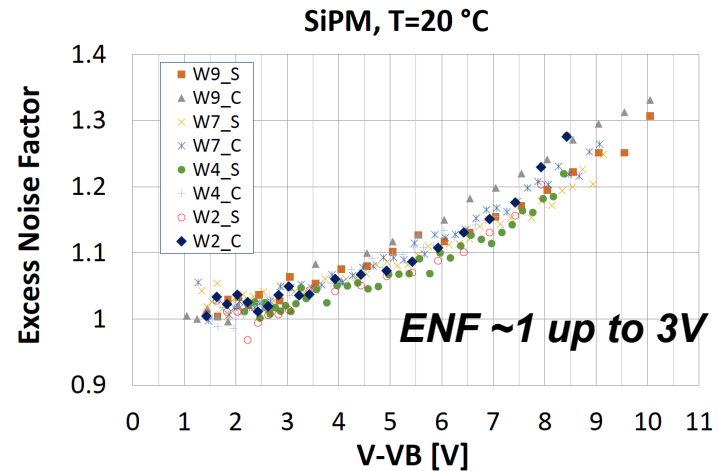
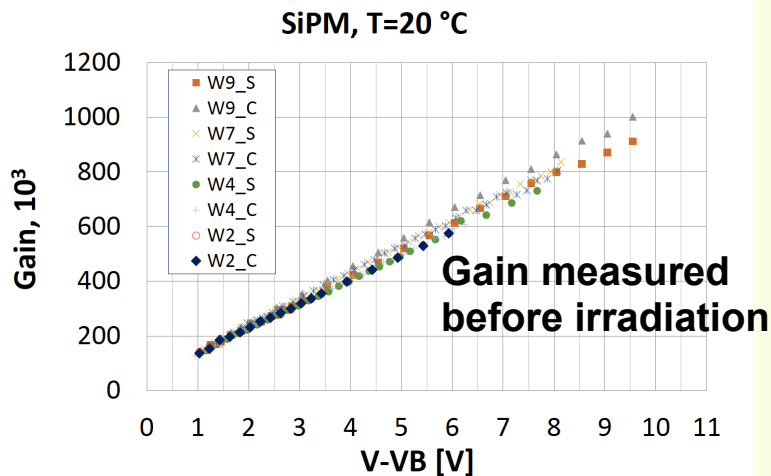
3 of these arrays were sent to JSI for passive irradiation for a total dose of $1E13$, $2E14$ and $4E14$

For direct comparison we also included 3 HPK 3x3 mm HDR2 for each dose





Average number of photons in LED pulse is measured using XP2020 calibrated: PMT (QE(410 nm)=25.0 %, ENF=1.15), and waveforms recorded by DSO



To measure S/N after irradiation we use constant light illumination from 405 nm LED source (calibrated uniform over the 8ch):

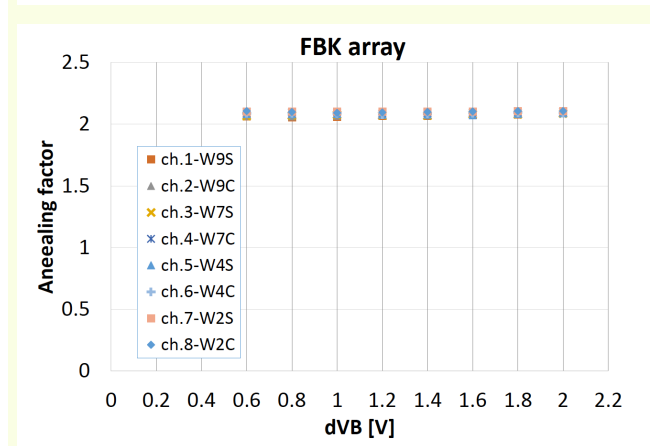
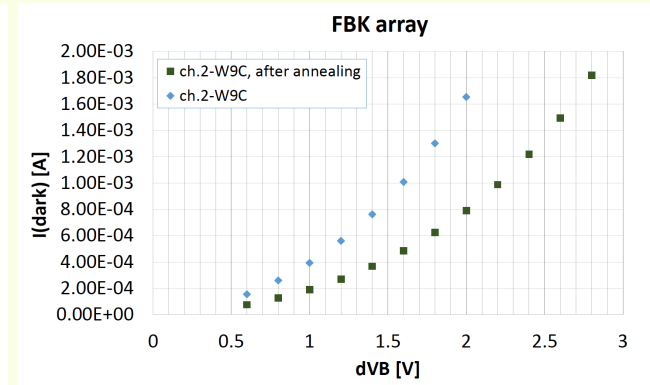
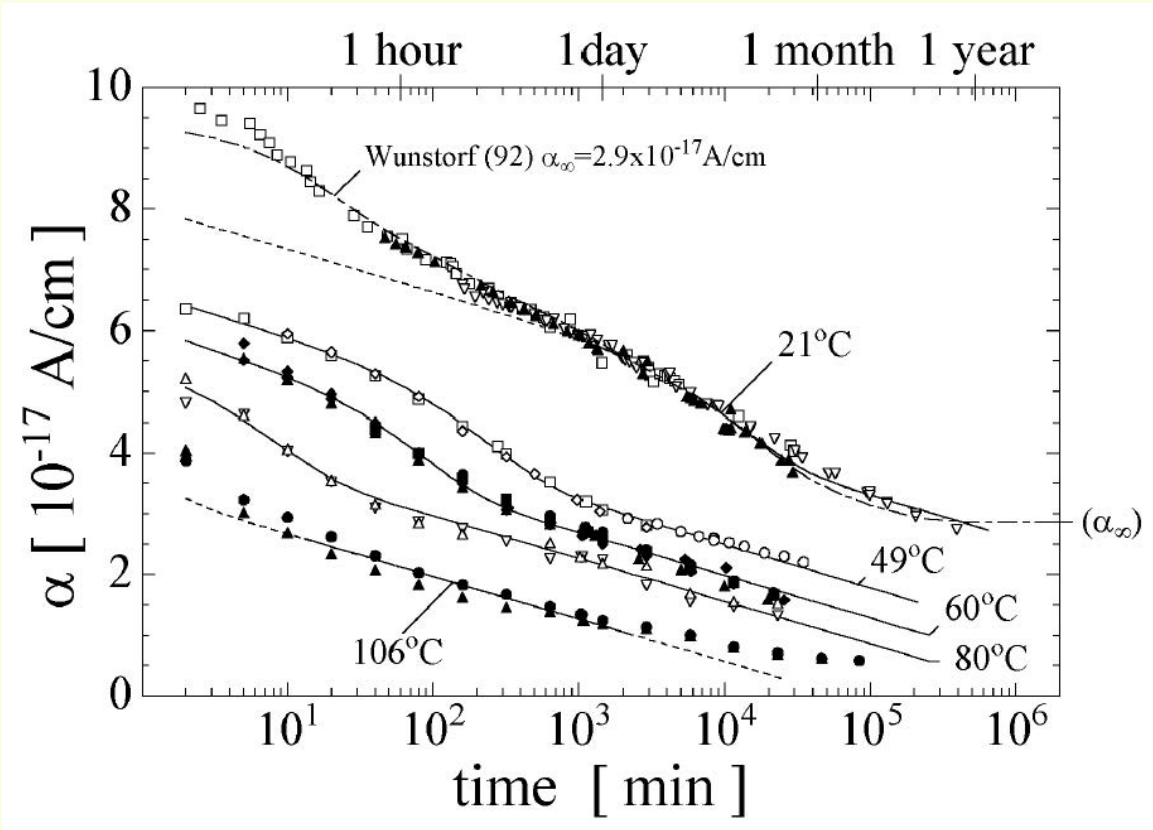
$I(\text{total}) = I(\text{ph}) + I(\text{dark}) = (I'_{\text{ph}} + I'_{\text{dark}}) \cdot \text{Gain} \cdot \text{ENF}$ with $\text{ENF} \sim 1$
 I'_{ph} and I'_{dark} are the primary generated currents (before amplification)
 $I(\text{total})$ and $I(\text{dark})$ are measured simultaneously (LED On and LED off)

$$I_{\text{ph current}} = I'_{\text{ph}} / 1.6 \times 10^{-19}$$

$$\text{DCR} = I'_{\text{dark}} / 1.6 \times 10^{-19}$$

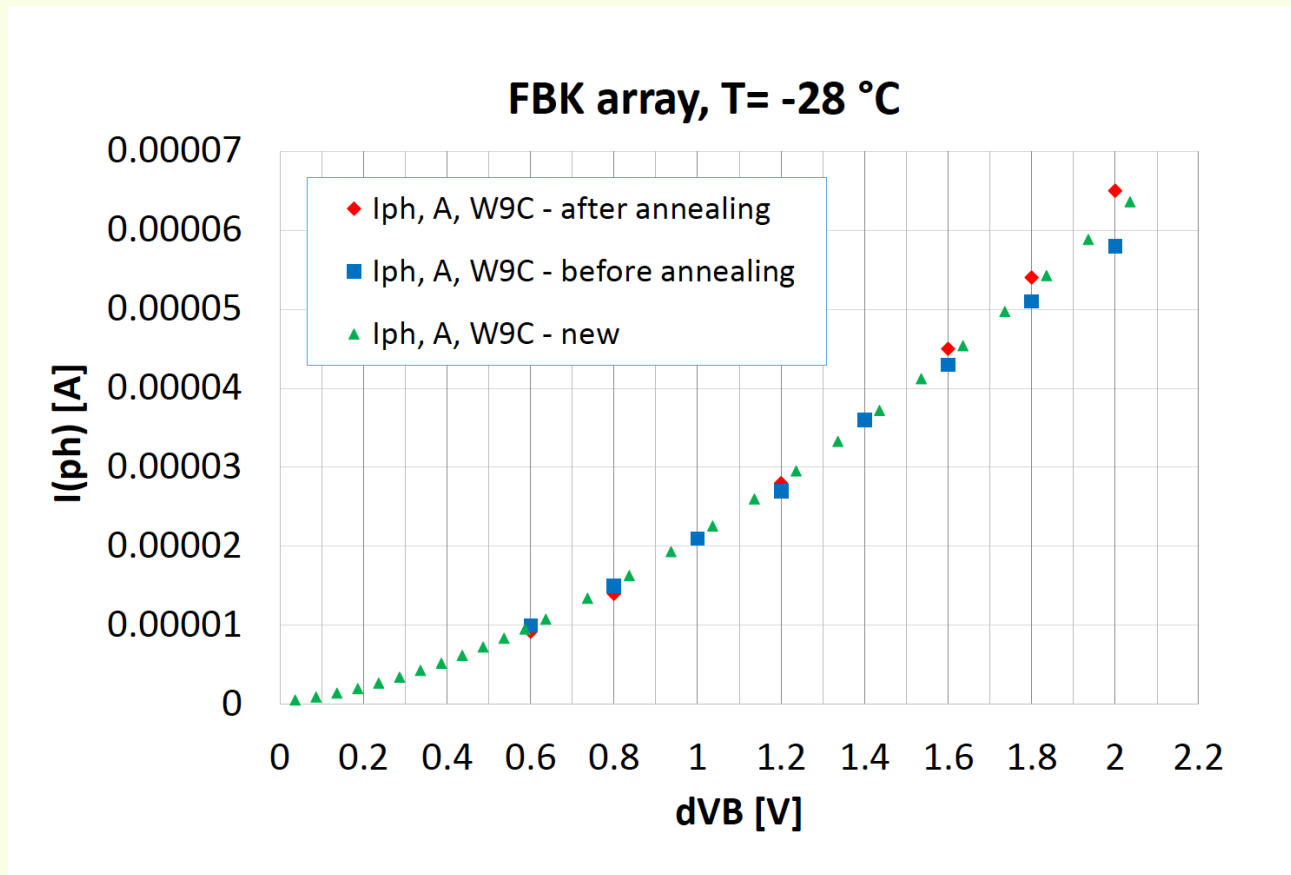
$$\text{S/N} = I_{\text{ph current}} / \text{DCR}$$

Silicon Annealing vs temperature

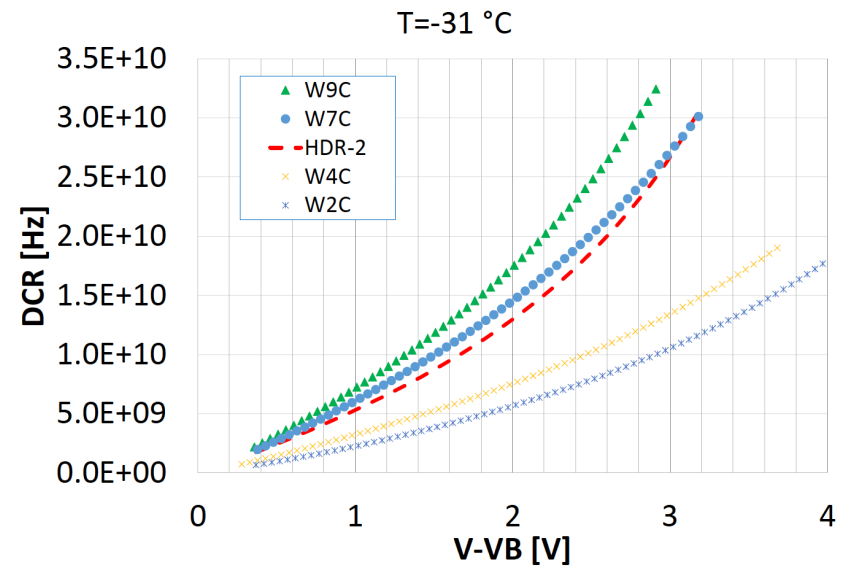
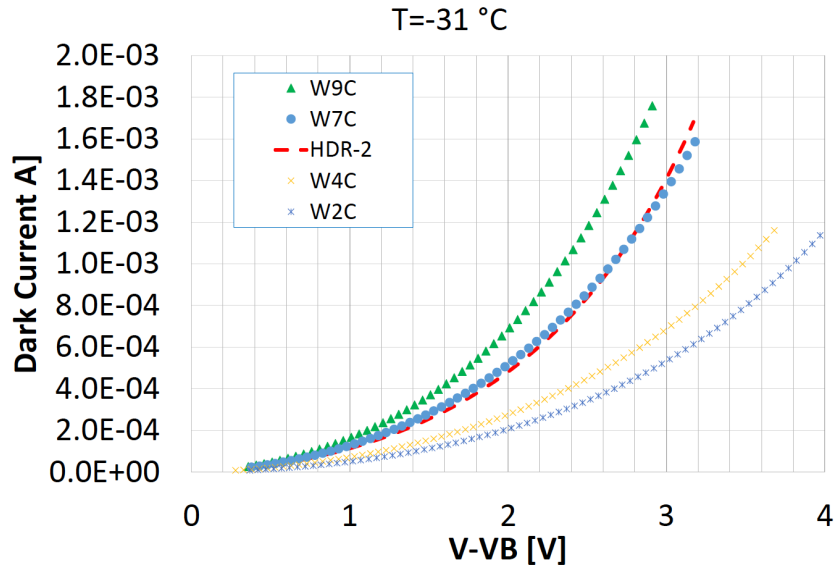


- We use 60C for 80 min to simulate RT annealing

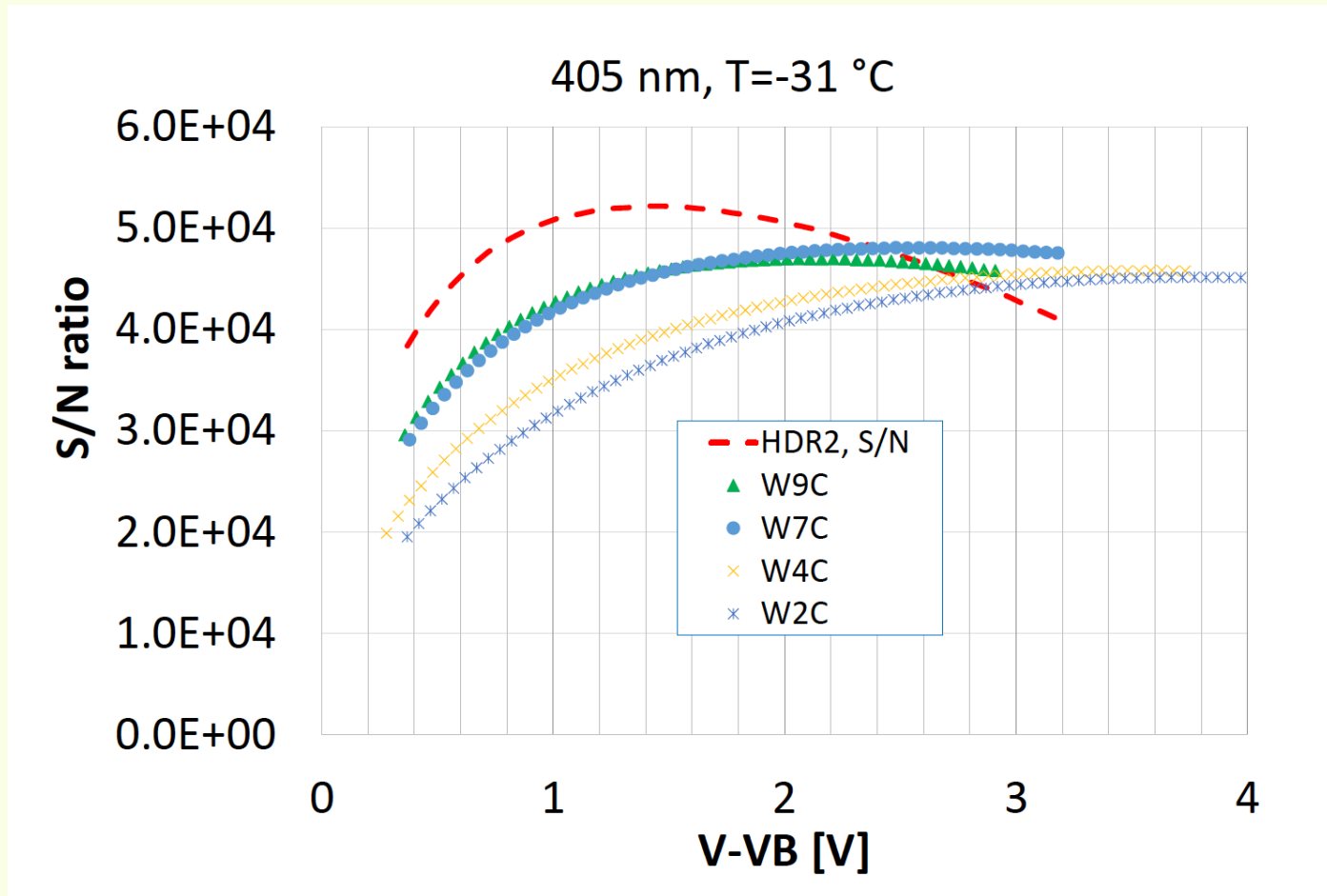
Dose = $1.4E13$ n/cm eq.



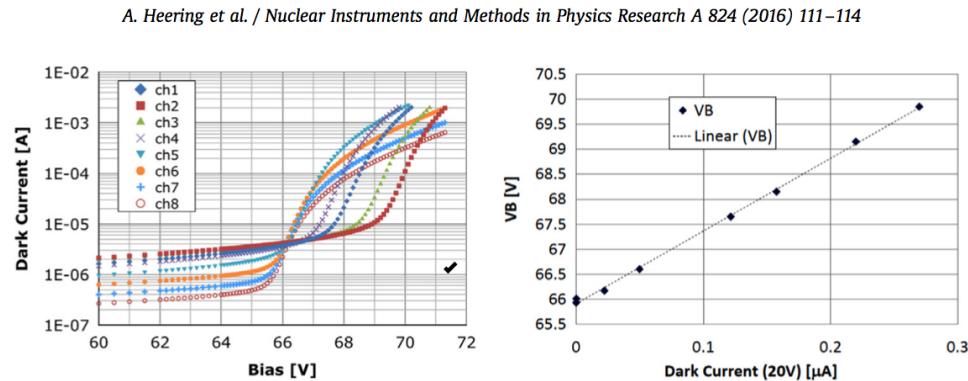
I(ph) is unchanged after irradiation and annealing:
Hence PDE, Gain and ENF are unchanged at this dose



Currents reach 2 mA at 3V over voltage which starts to cause self heating of the SiPM



Using the CERN IRRAD 24 GeV proton beam we irradiated a 8 ch Array with 10 micron HPK S12572 SiPMs



5x5 mm²
Beam, p



Fig. 3. 10 μm cell HPK 8 channel array with ø 2.8 mm SiPMs with a maximum dose of 2.2×10^{14} n/cm² in channel 2. (a) Dark current vs. bias voltage. (b) Bias voltage shift vs. dark current at gain 1.

Ch.2 – irradiated with 24 GeV protons ($\sim 2.2E14$ n/cm²)

Ch.8 – irradiated with 24 GeV protons ($\sim 7.5E12$ n/cm²)

**Due to Change of the doping concentration:
VB shift with fluence reaches 4 V at 2.2E14 n/cm²**

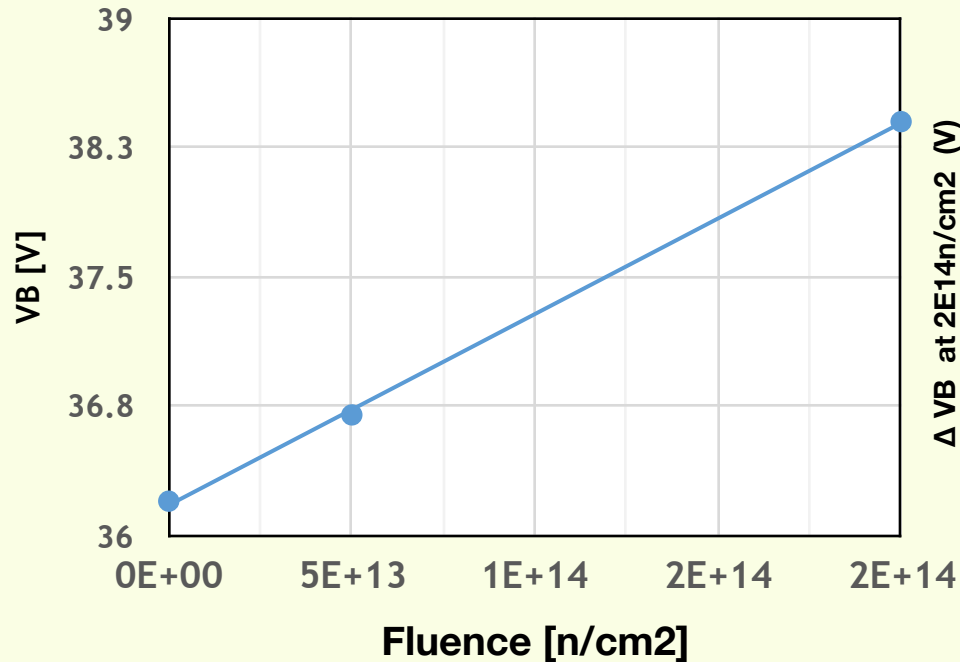
Vbr = 66 V at zero dose



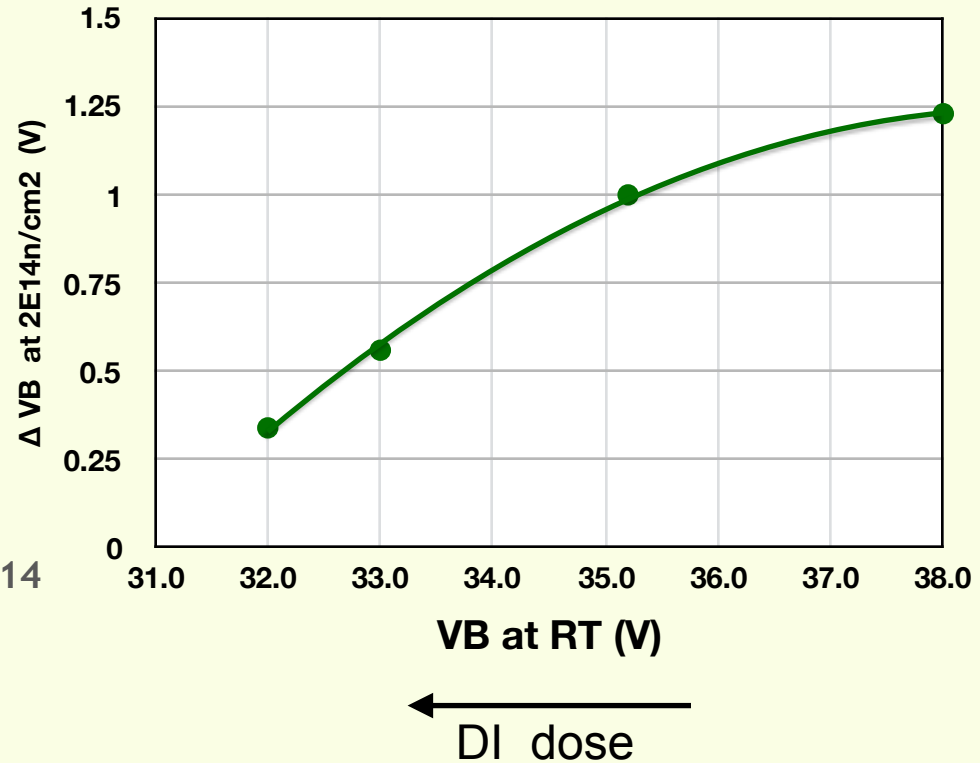
Measured Breakdown voltage shift at 2E14



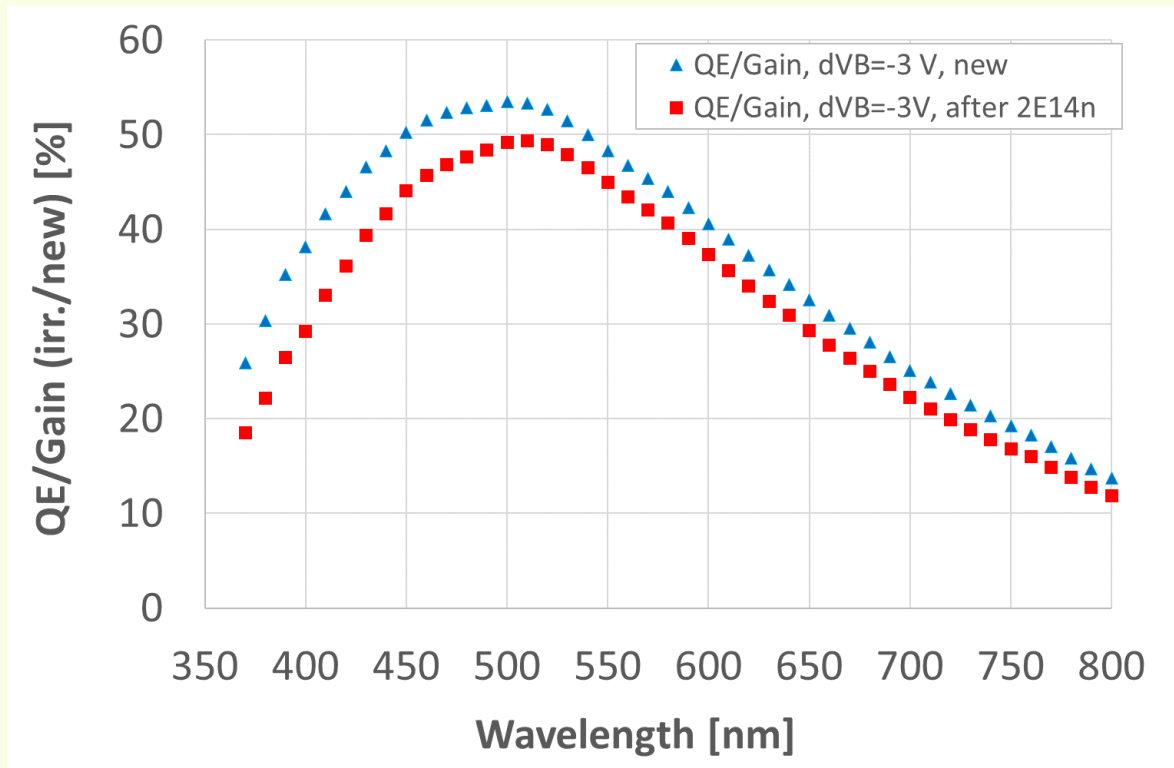
HDR2-3015 SiPM (T=-29.4 °C)



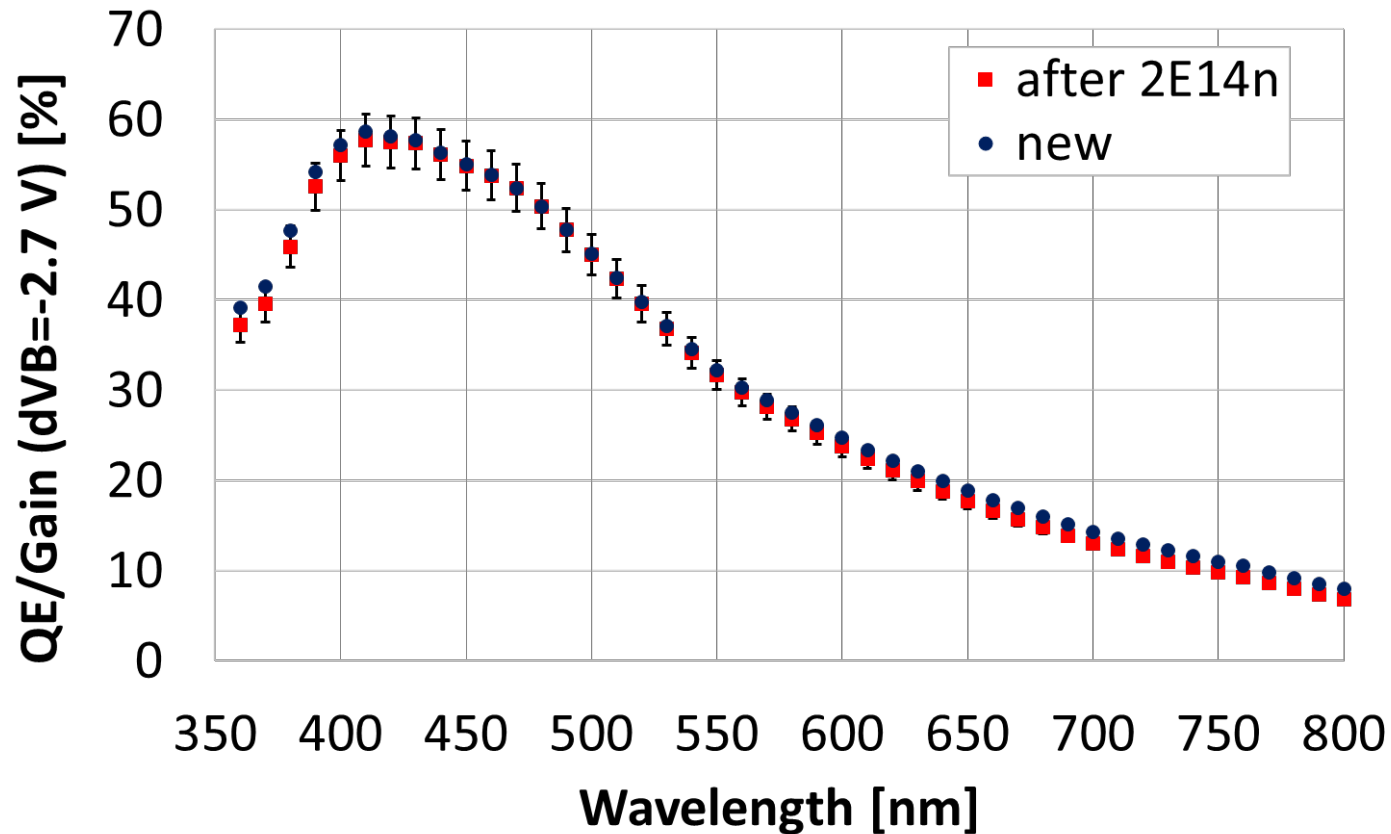
● FBK Wafer 9,7,4,2 HHF (C) (T= -31C)



Other EFFECT we found at 2E14 is QE loss

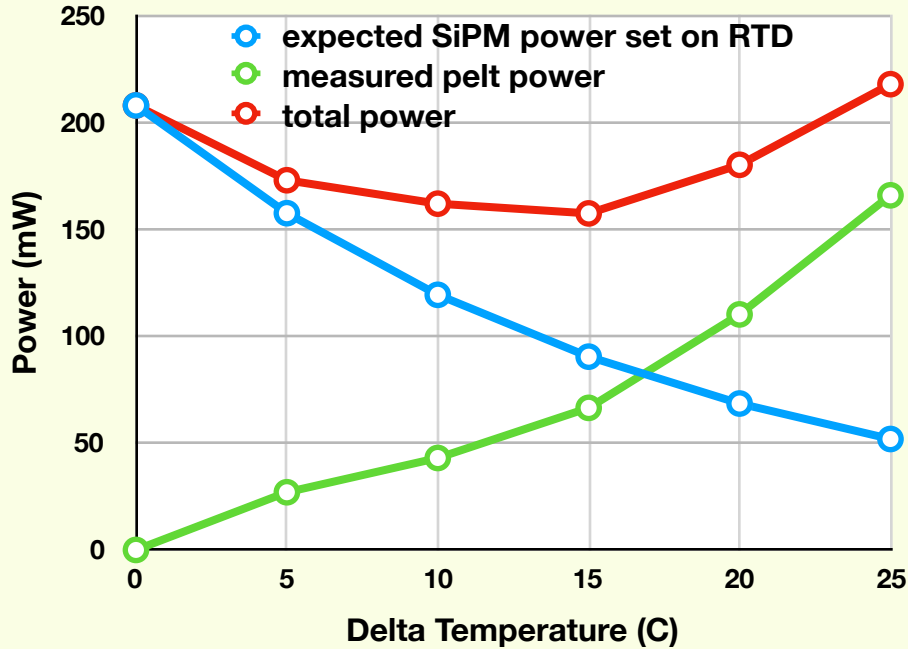


This could be a combination of ; Recombination of e-h in top p+ layer and Browning of protective resin used (under investigation)



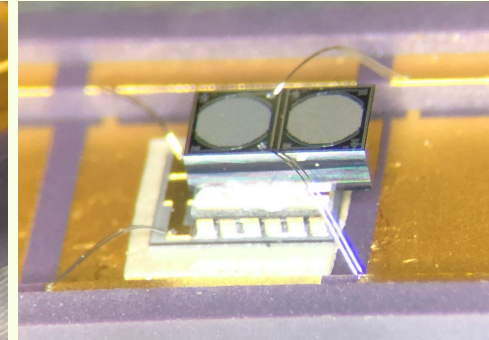
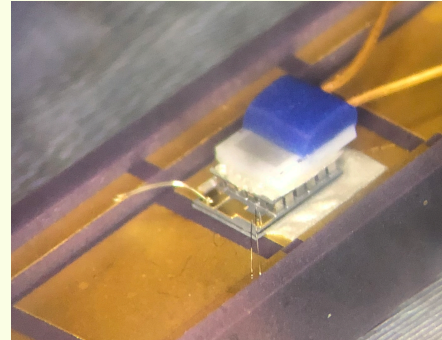
FBK with thinner top p+ layer

power consumption vs ΔT



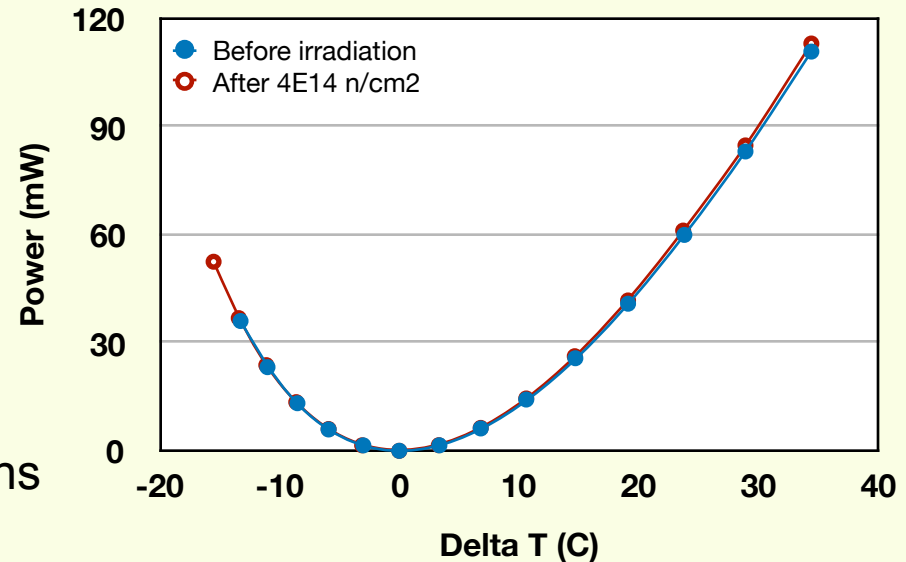
phononic

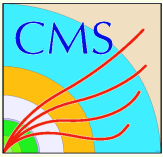
2x2x0.8 mm³



Advantage of the use of mini peltiers:

- ΔT of -20C without extra power
- Annealing at +60C during LHC shutdowns





Summary



After successful replacement of HPDs with SiPMs in the CMS HCAL in the last 6 years with a neutron dose of max $2E12$ n/cm²

We now plan to also use them in two more sub-detectors in CMS: HGCAL and BTL.

This brings significant new challenges due to the large fluence of $2E14$ n/cm² 1MeV eq. (Even though we will operate at -30C)

- Large DCR linear with the fluence
- Breakdown voltage shift due to change in doping concentration
- Self heating of the SiPMs due to the large gain
- Loss of PDE in front p+ layer and/or the protective resins used

We like to thank FBK and Hamamatsu for the commitment to this project and the progress made in the last years to improve the SiPMs for these projects

R&D will continue.....

